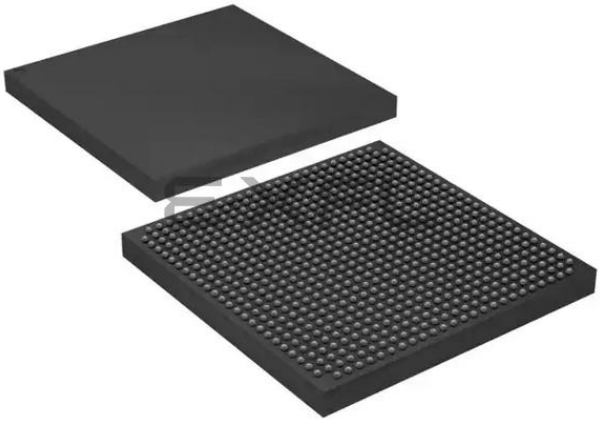

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Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	780
Number of Logic Elements/Cells	15600
Total RAM Bits	419328
Number of I/O	366
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	672-BBGA
Supplier Device Package	672-FBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2s15f672i4n

arithmetic chain runs vertically allowing fast horizontal connections to TriMatrix memory and DSP blocks. A shared arithmetic chain can continue as far as a full column.

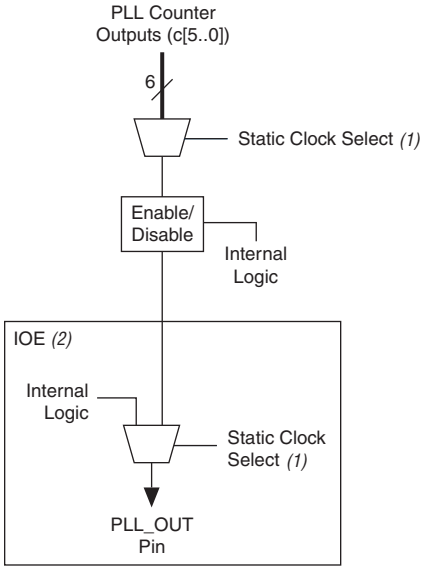
Similar to the carry chains, the shared arithmetic chains are also top- or bottom-half bypassable. This capability allows the shared arithmetic chain to cascade through half of the ALMs in a LAB while leaving the other half available for narrower fan-in functionality. Every other LAB column is top-half bypassable, while the other LAB columns are bottom-half bypassable.

See the "MultiTrack Interconnect" on page 2–22 section for more information on shared arithmetic chain interconnect.

Register Chain

In addition to the general routing outputs, the ALMs in an LAB have register chain outputs. The register chain routing allows registers in the same LAB to be cascaded together. The register chain interconnect allows an LAB to use LUTs for a single combinational function and the registers to be used for an unrelated shift register implementation. These resources speed up connections between ALMs while saving local interconnect resources (see Figure 2–15). The Quartus II Compiler automatically takes advantage of these resources to improve utilization and performance.

Figure 2–39. External PLL Output Clock Control Blocks



Notes to Figure 2–39:

(1) These clock select signals can only be set through a configuration file (**.sof** or **.pof**) and cannot be dynamically controlled during user mode operation.

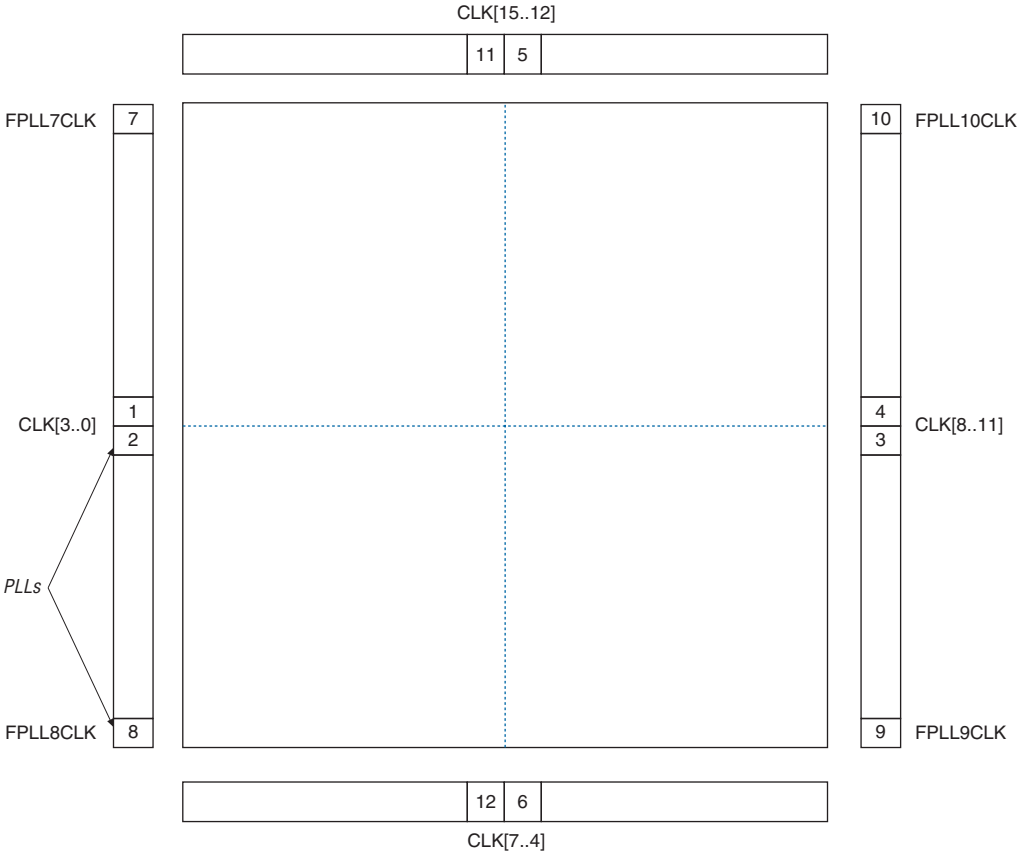
(2) The clock control block feeds to a multiplexer within the PLL_OUT pin's IOE. The PLL_OUT pin is a dual-purpose pin. Therefore, this multiplexer selects either an internal signal or the output of the clock control block.

For the global clock control block, the clock source selection can be controlled either statically or dynamically. The user has the option of statically selecting the clock source by using the Quartus II software to set specific configuration bits in the configuration file (**.sof** or **.pof**) or the user can control the selection dynamically by using internal logic to drive the multiplexor select inputs. When selecting statically, the clock source can be set to any of the inputs to the select multiplexor. When selecting the clock source dynamically, you can either select between two PLL outputs (such as the C0 or C1 outputs from one PLL), between two PLLs (such as the C0/C1 clock output of one PLL or the C0/C1 c1ock output of the other PLL), between two clock pins (such as CLK0 or CLK1), or between a combination of clock pins or PLL outputs. The clock outputs from corner PLLs cannot be dynamically selected through the global control block.

For the regional and PLL_OUT clock control block, the clock source selection can only be controlled statically using configuration bits. Any of the inputs to the clock select multiplexor can be set as the clock source.

Figure 2–40 shows a top-level diagram of the Stratix II device and PLL floorplan.

Figure 2–40. PLL Locations



Figures 2–41 and 2–42 shows the global and regional clocking from the fast PLL outputs and the side clock pins.

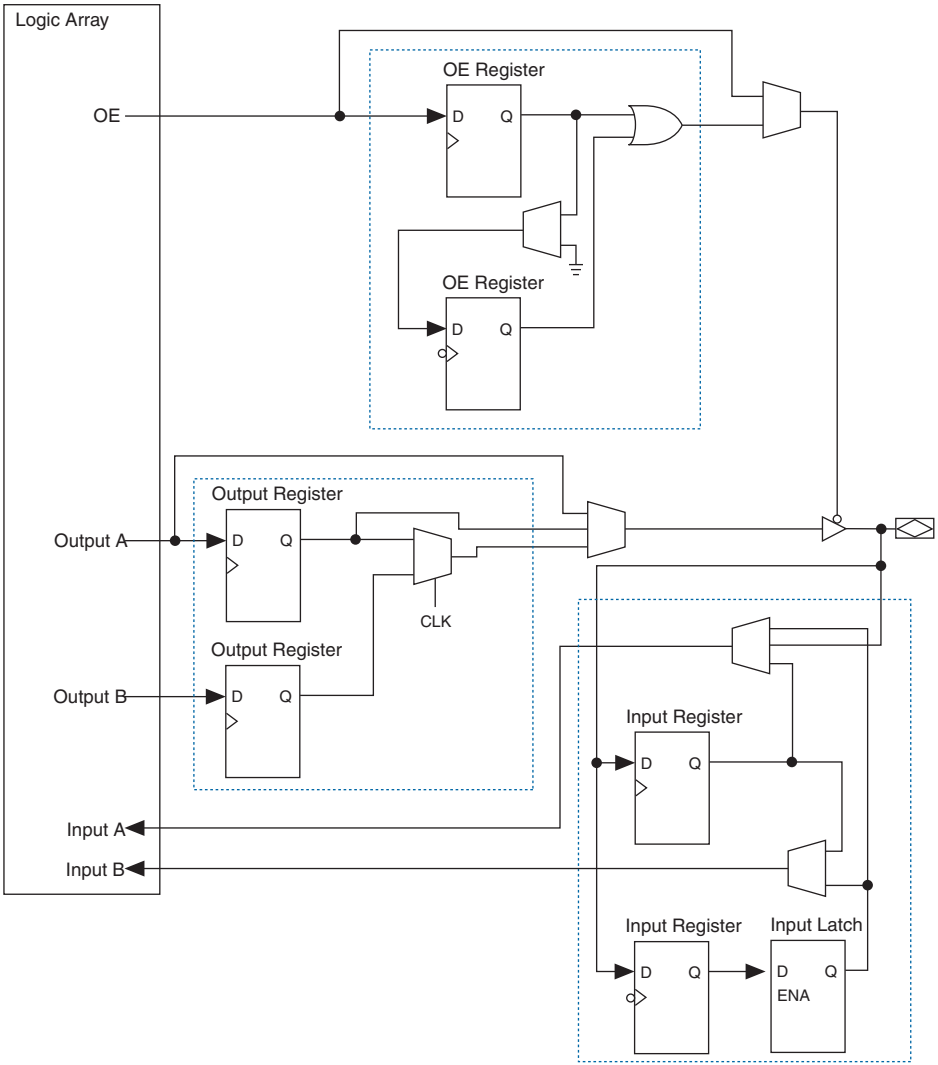
Table 2–11. Global & Regional Clock Connections from Top Clock Pins & Enhanced PLL Outputs (Part 1 of 2)

Top Side Global & Regional Clock Network Connectivity	DLLCLK	CLK12	CLK13	CLK14	CLK15	RCLK24	RCLK25	RCLK26	RCLK27	RCLK28	RCLK29	RCLK30	RCLK31
Clock pins													
CLK12p	✓	✓	✓			✓				✓			
CLK13p	✓	✓	✓				✓						✓
CLK14p	✓			✓	✓			✓				✓	
CLK15p	✓			✓	✓				✓		✓		
CLK12n		✓				✓				✓			
CLK13n			✓				✓						✓
CLK14n				✓				✓				✓	
CLK15n					✓				✓		✓		
Drivers from internal logic													
GCLKDRV0		✓											
GCLKDRV1			✓										
GCLKDRV2				✓									
GCLKDRV3					✓								
RCLKDRV0						✓				✓			
RCLKDRV1							✓				✓		
RCLKDRV2								✓				✓	
RCLKDRV3									✓				✓
RCLKDRV4						✓				✓			
RCLKDRV5							✓				✓		
RCLKDRV6								✓				✓	
RCLKDRV7									✓				✓
Enhanced PLL 5 outputs													
c0	✓	✓	✓			✓				✓			
c1	✓	✓	✓				✓				✓		
c2	✓			✓	✓			✓				✓	
c3	✓			✓	✓				✓				✓

- Output drive strength control
- Tri-state buffers
- Bus-hold circuitry
- Programmable pull-up resistors
- Programmable input and output delays
- Open-drain outputs
- DQ and DQS I/O pins
- Double data rate (DDR) registers

The IOE in Stratix II devices contains a bidirectional I/O buffer, six registers, and a latch for a complete embedded bidirectional single data rate or DDR transfer. Figure 2–46 shows the Stratix II IOE structure. The IOE contains two input registers (plus a latch), two output registers, and two output enable registers. The design can use both input registers and the latch to capture DDR input and both output registers to drive DDR outputs. Additionally, the design can use the output enable (OE) register for fast clock-to-output enable timing. The negative edge-clocked OE register is used for DDR SDRAM interfacing. The Quartus II software automatically duplicates a single OE register that controls multiple output or bidirectional pins.

Figure 2–46. Stratix II IOE Structure



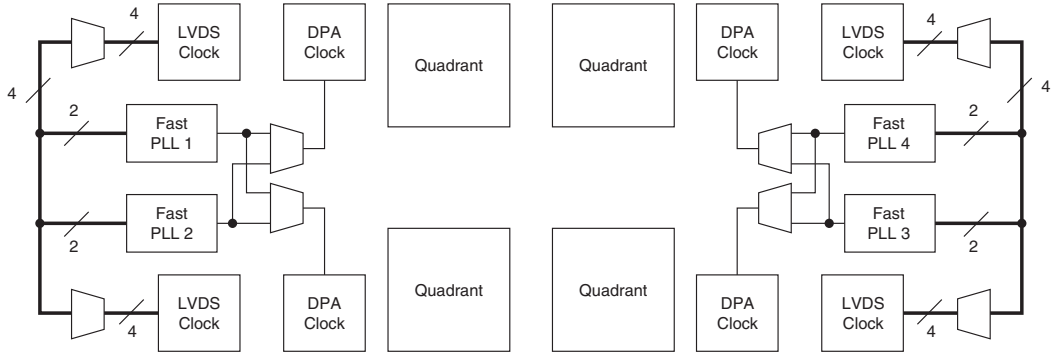
The IOEs are located in I/O blocks around the periphery of the Stratix II device. There are up to four IOEs per row I/O block and four IOEs per column I/O block. The row I/O blocks drive row, column, or direct link interconnects. The column I/O blocks drive column interconnects. Figure 2–47 shows how a row I/O block connects to the logic array. Figure 2–48 shows how a column I/O block connects to the logic array.

For high-speed source synchronous interfaces such as POS-PHY 4, Parallel RapidIO, and HyperTransport, the source synchronous clock rate is not a byte- or SERDES-rate multiple of the data rate. Byte alignment is necessary for these protocols since the source synchronous clock does not provide a byte or word boundary since the clock is one half the data rate, not one eighth. The Stratix II device's high-speed differential I/O circuitry provides dedicated data realignment circuitry for user-controlled byte boundary shifting. This simplifies designs while saving ALM resources. You can use an ALM-based state machine to signal the shift of receiver byte boundaries until a specified pattern is detected to indicate byte alignment.

Fast PLL & Channel Layout

The receiver and transmitter channels are interleaved such that each I/O bank on the left and right side of the device has one receiver channel and one transmitter channel per LAB row. Figure 2–60 shows the fast PLL and channel layout in the EP2S15 and EP2S30 devices. Figure 2–61 shows the fast PLL and channel layout in the EP2S60 to EP2S180 devices.

Figure 2–60. Fast PLL & Channel Layout in the EP2S15 & EP2S30 Devices *Note (1)*



Note to Figure 2–60:
(1) See Table 2–21 for the number of channels each device supports.

3. Configuration & Testing

SII51003-4.2

IEEE Std. 1149.1 JTAG Boundary-Scan Support

All Stratix® II devices provide Joint Test Action Group (JTAG) boundary-scan test (BST) circuitry that complies with the IEEE Std. 1149.1. JTAG boundary-scan testing can be performed either before or after, but not during configuration. Stratix II devices can also use the JTAG port for configuration with the Quartus® II software or hardware using either Jam Files (**.jam**) or Jam Byte-Code Files (**.jbc**).

Stratix II devices support IOE I/O standard setting reconfiguration through the JTAG BST chain. The JTAG chain can update the I/O standard for all input and output pins any time before or during user mode through the `CONFIG_IO` instruction. You can use this capability for JTAG testing before configuration when some of the Stratix II pins drive or receive from other devices on the board using voltage-referenced standards. Because the Stratix II device may not be configured before JTAG testing, the I/O pins may not be configured for appropriate electrical standards for chip-to-chip communication. Programming those I/O standards via JTAG allows you to fully test I/O connections to other devices.

A device operating in JTAG mode uses four required pins, `TDI`,`TDO`, `TMS`, and `TCK`, and one optional pin, `TRST`. The `TCK` pin has an internal weak pull-down resistor, while the `TDI`,`TMS` and `TRST` pins have weak internal pull-ups. The JTAG input pins are powered by the 3.3-V `VCCPD` pins. The TDO output pin is powered by the V_{CCIO} power supply of bank 4.

Stratix II devices also use the JTAG port to monitor the logic operation of the device with the SignalTap® II embedded logic analyzer. Stratix II devices support the JTAG instructions shown in Table 3–1.

Stratix II, Stratix, Cyclone® II, and Cyclone devices must be within the first 17 devices in a JTAG chain. All of these devices have the same JTAG controller. If any of the Stratix II, Stratix, Cyclone II, or Cyclone devices are in the 18th of further position, they fail configuration. This does not affect SignalTap II.

The Stratix II device instruction register length is 10 bits and the `USERCODE` register length is 32 bits. Tables 3–2 and 3–3 show the boundary-scan register length and device `IDCODE` information for Stratix II devices.

Table 3–7. Document Revision History (Part 2 of 2)

Date and Document Version	Changes Made	Summary of Changes
April 2006, v4.1	Updated "Device Security Using Configuration Bitstream Encryption" section.	—
December 2005, v4.0	Updated "Software Interface" section.	—
May 2005, v3.0	• Updated "IEEE Std. 1149.1 JTAG Boundary-Scan Support" section. • Updated "Operating Modes" section.	—
January 2005, v2.1	Updated JTAG chain device limits.	—
January 2005, v2.0	Updated Table 3–3.	—
July 2004, v1.1	• Added "Automated Single Event Upset (SEU) Detection" section. • Updated "Device Security Using Configuration Bitstream Encryption" section. • Updated Figure 3–2.	—
February 2004, v1.0	Added document to the Stratix II Device Handbook.	—

Table 5–19. SSTL-2 Class I Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		2.375	2.500	2.625	V
V_{TT}	Termination voltage		V_{REF} – 0.04	V_{REF}	V_{REF} + 0.04	V
V_{REF}	Reference voltage		1.188	1.250	1.313	V
V_{IH} (DC)	High-level DC input voltage		V_{REF} + 0.18		3.00	V
V_{IL} (DC)	Low-level DC input voltage		–0.30		V_{REF} – 0.18	V
V_{IH} (AC)	High-level AC input voltage		V_{REF} + 0.35			V
V_{IL} (AC)	Low-level AC input voltage				V_{REF} - 0.35	V
V_{OH}	High-level output voltage	I_{OH} = –8.1 mA *(1)*	V_{TT} + 0.57			V
V_{OL}	Low-level output voltage	I_{OL} = 8.1 mA *(1)*			V_{TT} – 0.57	V

Note to Table 5–19:

(1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Table 5–20. SSTL-2 Class II Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		2.375	2.500	2.625	V
V_{TT}	Termination voltage		V_{REF} – 0.04	V_{REF}	V_{REF} + 0.04	V
V_{REF}	Reference voltage		1.188	1.250	1.313	V
V_{IH} (DC)	High-level DC input voltage		V_{REF} + 0.18		V_{CCIO} + 0.30	V
V_{IL} (DC)	Low-level DC input voltage		–0.30		V_{REF} – 0.18	V
V_{IH} (AC)	High-level AC input voltage		V_{REF} + 0.35			V
V_{IL} (AC)	Low-level AC input voltage				V_{REF} - 0.35	V
V_{OH}	High-level output voltage	I_{OH} = –16.4 mA *(1)*	V_{TT} + 0.76			V
V_{OL}	Low-level output voltage	I_{OL} = 16.4 mA *(1)*			V_{TT} – 0.76	V

Note to Table 5–20:

(1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Table 5–25. 1.5-V HSTL Class I & II Differential Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	I/O supply voltage		1.425	1.500	1.575	V
V_{DIF} (DC)	DC input differential voltage		0.2			V
V_{CM} (DC)	DC common mode input voltage		0.68		0.90	V
V_{DIF} (AC)	AC differential input voltage		0.4			V
V_{OX} (AC)	AC differential cross point voltage		0.68		0.90	V

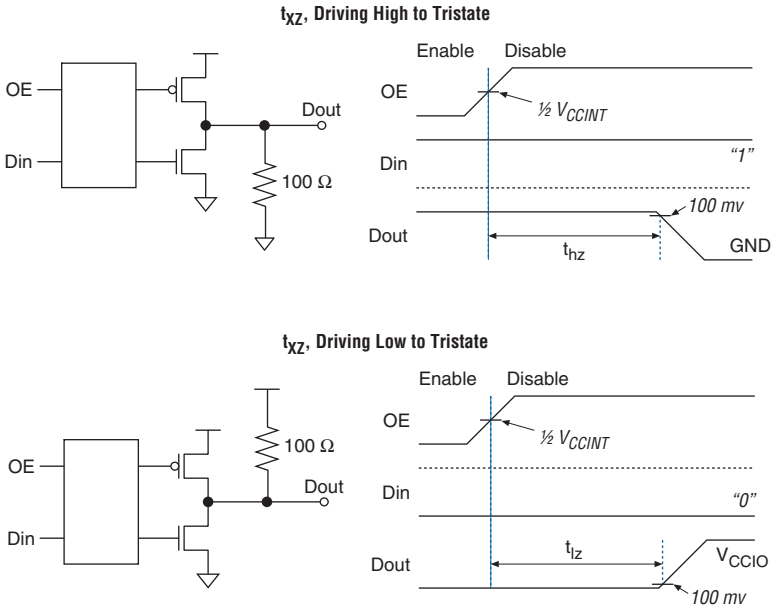
Table 5–26. 1.8-V HSTL Class I Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		1.71	1.80	1.89	V
V_{REF}	Input reference voltage		0.85	0.90	0.95	V
V_{TT}	Termination voltage		0.85	0.90	0.95	V
V_{IH} (DC)	DC high-level input voltage		V_{REF} + 0.1			V
V_{IL} (DC)	DC low-level input voltage		–0.3		V_{REF} – 0.1	V
V_{IH} (AC)	AC high-level input voltage		V_{REF} + 0.2			V
V_{IL} (AC)	AC low-level input voltage				V_{REF} – 0.2	V
V_{OH}	High-level output voltage	I_{OH} = 8 mA *(1)*	V_{CCIO} – 0.4			V
V_{OL}	Low-level output voltage	I_{OH} = –8 mA *(1)*			0.4	V

Note to Table 5–26:

(1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Figure 5–5. Measurement Setup for t_{xz} *Note (1)*



Note to Figure 5–5:
(1) V_{CCINT} is 1.12 V for this measurement.

Table 5–53. EP2S60 Column Pins Global Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.658	1.739	2.920	3.350	3.899	ns
t_{COUT}	1.501	1.574	2.678	3.072	3.575	ns
t_{PLLCIN}	0.06	0.057	0.278	0.304	0.355	ns
$t_{PLLCOUT}$	-0.097	-0.108	0.036	0.026	0.031	ns

Table 5–54. EP2S60 Row Pins Regional Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.463	1.532	2.591	2.972	3.453	ns
t_{COUT}	1.468	1.537	2.587	2.968	3.448	ns
t_{PLLCIN}	-0.153	-0.167	-0.079	-0.099	-0.128	ns
$t_{PLLCOUT}$	-0.148	-0.162	-0.083	-0.103	-0.133	ns

Table 5–55. EP2S60 Row Pins Global Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.439	1.508	2.562	2.940	3.421	ns
t_{COUT}	1.444	1.513	2.558	2.936	3.416	ns
t_{PLLCIN}	-0.161	-0.174	-0.083	-0.107	-0.126	ns
$t_{PLLCOUT}$	-0.156	-0.169	-0.087	-0.111	-0.131	ns

I/O Delays

See Tables 5–72 through 5–76 for I/O delays.

Table 5–72. I/O Delay Parameters

Symbol	Parameter
t_{DIP}	Delay from I/O datain to output pad
t_{OP}	Delay from I/O output register to output pad
t_{PCOUT}	Delay from input pad to I/O dataout to core
t_{PI}	Delay from input pad to I/O input register

Table 5–73. Stratix II I/O Input Delay for Column Pins (Part 1 of 3)

I/O Standard	Parameter	Minimum Timing		-3 Speed Grade (2)	-3 Speed Grade (3)	-4 Speed Grade	-5 Speed Grade	Unit
		Industrial	Commercial					
LVTTL	t_{PI}	674	707	1223	1282	1405	1637	ps
	t_{PCOUT}	408	428	787	825	904	1054	ps
2.5 V	t_{PI}	684	717	1210	1269	1390	1619	ps
	t_{PCOUT}	418	438	774	812	889	1036	ps
1.8 V	t_{PI}	747	783	1366	1433	1570	1829	ps
	t_{PCOUT}	481	504	930	976	1069	1246	ps
1.5 V	t_{PI}	749	786	1436	1506	1650	1922	ps
	t_{PCOUT}	483	507	1000	1049	1149	1339	ps
LVCMOS	t_{PI}	674	707	1223	1282	1405	1637	ps
	t_{PCOUT}	408	428	787	825	904	1054	ps
SSTL-2 Class I	t_{PI}	507	530	818	857	939	1094	ps
	t_{PCOUT}	241	251	382	400	438	511	ps
SSTL-2 Class II	t_{PI}	507	530	818	857	939	1094	ps
	t_{PCOUT}	241	251	382	400	438	511	ps
SSTL-18 Class I	t_{PI}	543	569	898	941	1031	1201	ps
	t_{PCOUT}	277	290	462	484	530	618	ps
SSTL-18 Class II	t_{PI}	543	569	898	941	1031	1201	ps
	t_{PCOUT}	277	290	462	484	530	618	ps
1.5-V HSTL Class I	t_{PI}	560	587	993	1041	1141	1329	ps
	t_{PCOUT}	294	308	557	584	640	746	ps

Table 5–75. Stratix II I/O Output Delay for Column Pins (Part 6 of 8)

I/O Standard	Drive Strength	Parameter	Minimum Timing		-3 Speed Grade (3)	-3 Speed Grade (4)	-4 Speed Grade	-5 Speed Grade	Unit
			Industrial	Commercial					
Differential SSTL-2 Class I	8 mA	t_{OP}	913	957	1715	1799	1971	2041	ps
		t_{DIP}	933	979	1781	1869	2047	2131	ps
	12 mA	t_{OP}	896	940	1672	1754	1921	1991	ps
		t_{DIP}	916	962	1738	1824	1997	2081	ps
Differential SSTL-2 Class II	16 mA	t_{OP}	876	918	1609	1688	1849	1918	ps
		t_{DIP}	896	940	1675	1758	1925	2008	ps
	20 mA	t_{OP}	877	919	1598	1676	1836	1905	ps
		t_{DIP}	897	941	1664	1746	1912	1995	ps
	24 mA	t_{OP}	872	915	1596	1674	1834	1903	ps
		t_{DIP}	892	937	1662	1744	1910	1993	ps
Differential SSTL-18 Class I	4 mA	t_{OP}	909	953	1690	1773	1942	2012	ps
		t_{DIP}	929	975	1756	1843	2018	2102	ps
	6 mA	t_{OP}	914	958	1656	1737	1903	1973	ps
		t_{DIP}	934	980	1722	1807	1979	2063	ps
	8 mA	t_{OP}	894	937	1640	1721	1885	1954	ps
		t_{DIP}	914	959	1706	1791	1961	2044	ps
	10 mA	t_{OP}	898	942	1638	1718	1882	1952	ps
		t_{DIP}	918	964	1704	1788	1958	2042	ps
	12 mA	t_{OP}	891	936	1626	1706	1869	1938	ps
		t_{DIP}	911	958	1692	1776	1945	2028	ps
Differential SSTL-18 Class II	8 mA	t_{OP}	883	925	1597	1675	1835	1904	ps
		t_{DIP}	903	947	1663	1745	1911	1994	ps
	16 mA	t_{OP}	894	937	1578	1655	1813	1882	ps
		t_{DIP}	914	959	1644	1725	1889	1972	ps
	18 mA	t_{OP}	890	933	1585	1663	1821	1890	ps
		t_{DIP}	910	955	1651	1733	1897	1980	ps
	20 mA	t_{OP}	890	933	1583	1661	1819	1888	ps
		t_{DIP}	910	955	1649	1731	1895	1978	ps

Table 5–78. Maximum Output Toggle Rate on Stratix II Devices (Part 3 of 5) *Note (1)*

I/O Standard	Drive Strength	Column I/O Pins (MHz)			Row I/O Pins (MHz)			Clock Outputs (MHz)		
		-3	-4	-5	-3	-4	-5	-3	-4	-5
Differential SSTL-18 Class I *(3)*	4 mA	200	150	150	200	150	150	200	150	150
	6 mA	350	250	200	350	250	200	350	250	200
	8 mA	450	300	300	450	300	300	450	300	300
	10 mA	500	400	400	500	400	400	500	400	400
	12 mA	700	550	400	350	350	297	650	550	400
Differential SSTL-18 Class II *(3)*	8 mA	200	200	150	-	-	-	200	200	150
	16 mA	400	350	350	-	-	-	400	350	350
	18 mA	450	400	400	-	-	-	450	400	400
	20 mA	550	500	450	-	-	-	550	500	450
1.8-V Differential HSTL Class I *(3)*	4 mA	300	300	300	-	-	-	300	300	300
	6 mA	500	450	450	-	-	-	500	450	450
	8 mA	650	600	600	-	-	-	650	600	600
	10 mA	700	650	600	-	-	-	700	650	600
	12 mA	700	700	650	-	-	-	700	700	650
1.8-V Differential HSTL Class II *(3)*	16 mA	500	500	450	-	-	-	500	500	450
	18 mA	550	500	500	-	-	-	550	500	500
	20 mA	650	550	550	-	-	-	550	550	550
1.5-V Differential HSTL Class I *(3)*	4 mA	350	300	300	-	-	-	350	300	300
	6 mA	500	500	450	-	-	-	500	500	450
	8 mA	700	650	600	-	-	-	700	650	600
	10 mA	700	700	650	-	-	-	700	700	650
	12 mA	700	700	700	-	-	-	700	700	700
1.5-V Differential HSTL Class II *(3)*	16 mA	600	600	550	-	-	-	600	600	550
	18 mA	650	600	600	-	-	-	650	600	600
	20 mA	700	650	600	-	-	-	700	650	600
3.3-V PCI		1,000	790	670	-	-	-	1,000	790	670
3.3-V PCI-X		1,000	790	670	-	-	-	1,000	790	670
LVDS *(6)*		-	-	-	500	500	500	450	400	300
HyperTransport technology *(4)*, *(6)*					500	500	500	-	-	-
LVPECL *(5)*		-	-	-	-	-	-	450	400	300
3.3-V LVTTL	OCT 50 Ω	400	400	350	400	400	350	400	400	350
2.5-V LVTTL	OCT 50 Ω	350	350	300	350	350	300	350	350	300

Therefore, the DCD percentage for the 267 MHz SSTL-2 Class II non-DDIO row output clock on a –3 device ranges from 47.5% to 52.5%.

Table 5–81. Maximum DCD for Non-DDIO Output on Column I/O Pins *Note (1)*

Column I/O Output Standard I/O Standard	Maximum DCD for Non-DDIO Output		Unit
	-3 Devices	-4 & -5 Devices	
3.3-V LVTTL	190	220	ps
3.3-V LVCMOS	140	175	ps
2.5 V	125	155	ps
1.8 V	80	110	ps
1.5-V LVCMOS	185	215	ps
SSTL-2 Class I	105	135	ps
SSTL-2 Class II	100	130	ps
SSTL-18 Class I	90	115	ps
SSTL-18 Class II	70	100	ps
1.8-V HSTL Class I	80	110	ps
1.8-V HSTL Class II	80	110	ps
1.5-V HSTL Class I	85	115	ps
1.5-V HSTL Class II	50	80	ps
1.2-V HSTL *(2)*	170	-	ps
LVPECL	55	80	ps

Notes to Table 5–81:
(1) The DCD specification is based on a no logic array noise condition.
(2) 1.2-V HSTL is only supported in -3 devices.

Table 5–82. Maximum DCD for DDIO Output on Row I/O Pins Without PLL in the Clock Path for -3 Devices *Notes (1), (2)*

Row DDIO Output I/O Standard	Maximum DCD Based on I/O Standard of Input Feeding the DDIO Clock Port (No PLL in Clock Path)					Unit
	TTL/CMOS		SSTL-2	SSTL/HSTL	LVDS/ HyperTransport Technology	
	3.3 & 2.5 V	1.8 & 1.5 V	2.5 V	1.8 & 1.5 V	3.3 V	
3.3-V LVTTL	260	380	145	145	110	ps
3.3-V LVCMOS	210	330	100	100	65	ps
2.5 V	195	315	85	85	75	ps
1.8 V	150	265	85	85	120	ps
1.5-V LVCMOS	255	370	140	140	105	ps
SSTL-2 Class I	175	295	65	65	70	ps
SSTL-2 Class II	170	290	60	60	75	ps
SSTL-18 Class I	155	275	55	50	90	ps
1.8-V HSTL Class I	150	270	60	60	95	ps
1.5-V HSTL Class I	150	270	55	55	90	ps
LVDS/ HyperTransport technology	180	180	180	180	180	ps

Notes to Table 5–82:
(1) The information in Table 5–82 assumes the input clock has zero DCD.
(2) The DCD specification is based on a no logic array noise condition.

Here is an example for calculating the DCD in percentage for a DDIO output on a row I/O on a -3 device:

If the input I/O standard is SSTL-2 and the DDIO output I/O standard is SSTL-2 Class II, the maximum DCD is 60 ps (see Table 5–82). If the clock frequency is 267 MHz, the clock period T is:

$$T = 1/f = 1 / 267\ \text{MHz} = 3.745\ \text{ns} = 3745\ \text{ps}$$

Calculate the DCD as a percentage:

$(T/2 - DCD) / T = (3745\text{ps}/2 - 60\text{ps}) / 3745\text{ps} = 48.4\%$ (for low boundary)

$(T/2 + DCD) / T = (3745\ \text{ps}/2 + 60\ \text{ps}) / 3745\text{ps} = 51.6\%$ (for high boundary)

External Memory Interface Specifications

Tables 5–94 through 5–101 contain Stratix II device specifications for the dedicated circuitry used for interfacing with external memory devices.

Table 5–94. DLL Frequency Range Specifications

Frequency Mode	Frequency Range	Resolution (Degrees)
0	100 to 175	30
1	150 to 230	22.5
2	200 to 310	30
3	240 to 400 (–3 speed grade)	36
	240 to 350 (–4 and –5 speed grades)	36

Table 5–95 lists the maximum delay in the fast timing model for the Stratix II DQS delay buffer. Multiply the number of delay buffers that you are using in the DQS logic block to get the maximum delay achievable in your system. For example, if you implement a 90° phase shift at 200 MHz, you use three delay buffers in mode 2. The maximum achievable delay from the DQS block is then 3 × .416 ps = 1.248 ns.

Table 5–95. DQS Delay Buffer Maximum Delay in Fast Timing Model

Frequency Mode	Maximum Delay Per Delay Buffer (Fast Timing Model)	Unit
0	0.833	ns
1, 2, 3	0.416	ns

Table 5–96. DQS Period Jitter Specifications for DLL-Delayed Clock (tDQS_JITTER) *Note (1)*

Number of DQS Delay Buffer Stages *(2)*	Commercial	Industrial	Unit
1	80	110	ps
2	110	130	ps
3	130	180	ps
4	160	210	ps

Notes to Table 5–96:
(1) Peak-to-peak period jitter on the phase shifted DQS clock.
(2) Delay stages used for requested DQS phase shift are reported in your project's Compilation Report in the Quartus II software.

Table 5–103. Document Revision History (Part 3 of 3)

Date and Document Version	Changes Made	Summary of Changes
January 2005, v2.0	• Updated the "Power Consumption" section. • Added the "High-Speed I/O Specifications" and "On-Chip Termination Specifications" sections. • Removed the ESD Protection Specifications section. • Updated Tables 5–3 through 5–13, 5–16 through 5–18, 5–21, 5–35, 5–39, and 5–40. • Updated tables in "Timing Model" section. • Added Tables 5–30 and 5–31.	—
October 2004, v1.2	• Updated Table 5–3. • Updated introduction text in the "PLL Timing Specifications" section.	—
July 2004, v1.1	• Re-organized chapter. • Added typical values and C_{OUTFB} to Table 5–32. • Added undershoot specification to Note (4) for Tables 5–1 through 5–9. • Added Note (1) to Tables 5–5 and 5–6. • Added V_{ID} and V_{ICM} to Table 5–10. • Added "I/O Timing Measurement Methodology" section. • Added Table 5–72. • Updated Tables 5–1 through 5–2 and Tables 5–24 through 5–29.	—
February 2004, v1.0	Added document to the Stratix II Device Handbook.	—